

The 8th International Symposium on
Measurement Technology and Intelligent Instruments

25-27 September 2007
Tohoku University, Sendai, Japan

Organized by

International Committee on Measurements and Instrumentation (ICMI)
Japan Society for Precision Engineering (JSPE)
Korean Society for Precision Engineering (KSPE)
Chinese Society for Measurement (CSM)
Tohoku University, Research Center for Precision Nanosystems

In cooperation with

UNC Charlotte, Center for Precision Metrology
SIMTech, Singapore Institute of Manufacturing Technology

www.ismtii2007.mech.tohoku.ac.jp

ISMTII 2007

Call for Papers



Conference Scope:

The scope of the papers can be focused on, but not limited to, the following areas:

- Applied sensor technology
- Bio-measurement
- Dimensional measurement
- In-process and on-line measurement
- Machine tool metrology
- Mechanical measurement
- Intelligent measurement and instrumentation
- Micro/nano-metrology
- Precision measurement
- Metrology and characterization of materials
- Micro-sensor
- Process measurement
- Optical metrology and image processing
- Sensors and actuators
- Signal processing
- Uncertainty, traceability and calibration
- Software for instruments
- Surface metrology

Technical Sessions and Publications:

The technical sessions will include Keynote Speeches, Invited Paper Sessions, Ordinary Oral Sessions and Poster Sessions. Invited Paper Sessions and Ordinary Oral Sessions only accept full papers (six pages in A4 size). Poster Sessions accept both full papers (six pages in A4 size) and short papers (two pages in A4 size). All the papers will be printed in the conference proceedings that will be distributed in the conference.

The qualified full papers will be published in the journal of Key Engineering Materials (KEM), which is covered by SCI. To assure the conference quality, the papers, especially those will be presented in the oral sessions and published in the journal, will be strictly reviewed by multiple reviewers.

Keynote Speeches:



- Achieving traceability and sub-nanometer uncertainty using interferometric techniques
Dr. Han Haitjema,
Mitutoyo Research Center Europe
B.V., The Netherlands



- Engineering nanotechnology: The top down approach
Professor Robert J. Hocken,
The University of North Carolina
at Charlotte, USA



- Femtosecond pulse lasers for advanced precision optical metrology
Professor Seung-Woo Kim,
Korea Advanced Institute of Science and
Technology (KAIST), Korea



- Uncertainty estimation for coordinate metrology: calibration, form deviation and strategy of measurement
Professor Kiyoshi Takamasu,
The University of Tokyo, Japan

Invited Paper Sessions:

A number of Invited Paper Sessions are planned in ISMTII 2007. The Invited Paper Sessions are aimed at providing focused discussion on new and timely research topics and innovative issues on measurement technology and intelligent instruments. Authors who are interested in submitting papers to the Invited Paper Sessions, please contact the Session Chairs directly.

- High precision optical measurement of mass and force,
Chair: Prof. Y. Fujii, Gunma University, Japan
- Interferometers and laser self-mixing interferometers,
Chair: Prof. S. L. Zhang, Tsinghua University, China
- Measurements for bio and tissue engineering applications,
Chair: Prof. Alan K. T. Lau, Hong Kong Polytechnic Univ.,
Hong Kong
- Measurement method of motion and machining errors for
ultra-precision machines, Chair: Dr. C. H. Park, KIMM, Korea
- Nanomechanical testing, Chair: Dr. H. Huang, The University
of Queensland, Australia
- Online and in-process measurement, Chair: Prof. Y. Gao,
Hong Kong Univ. of Science and Technology, Hong Kong
- Optical measurements for semiconductor manufacturing,
Chair: Dr. Y. Zhang, SIMTech, Singapore
- Precision measurements for micro- and nanotechnology,
Chair: Dr. M. Krystek, PTB, Germany
- Sensors distinguished by enhanced measuring data validity
and long lifetime, Chairs: Dr. K. Sapozhnikova, Dr. R.
Taymanov, D.I.Mendeleev Institute for Metrology, Russia
- Sensors for intelligent robot, Chair: Prof. K. C. Fan, National
Taiwan University, Taiwan
- Traceable dimensional metrology, Chairs: Dr. T. Takatsuji,
AIST, Japan, Prof. M. Komori, Kyoto University, Japan

Important Dates:

Submission of abstracts : 2007.02.01
Notification of abstract acceptance: 2007.02.15
Submission of manuscripts of Full Papers: 2007.04.15
Notification of Full Paper acceptance: 2007.06.01
Submission of revised Full Papers: 2007.07.01

Registration Fees:

Registration fees (covering Welcome Party, Conference
Dinner, Lunches and a hard copy of Proceedings)
Ordinary registration: JPY35,000
Student registration: JPY20,000
Publication fee for KEM: EUR120 for each paper to be published on
KEM in addition to a mailing cost for delivery of the hardcopy.

Conference Homepage:

<http://www.ismtii2007.mech.tohoku.ac.jp/>
Please visit the above homepage for detailed information on
the conference including paper submission, conference
registration, hotel reservation, etc.

For Contact:

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